PCN Number: 201904		24000.1					ate:	Apr 24, 2019
Title: Qualify new Mount Compound Material for Select Package Device								
Customer Contact: PCN Manager Dept: Quality Services								
Proposed 1 st Ship Date:		Jul. 24, 2019			Estimated Sam			
Availability: sample request							ole request	
Change Type: Assembly Site Design Wafer Bump Site 							n Site	
Assembly Process			Data Sheet			Wafer Bump Material		
Assembly Materials			Part number change			Wafer Bump Process		
Mechanical Specification			Test Site		Wafe	Wafer Fab Site		
Packing/Shipping/Label		ng	Test Process			Wafer Fab Materials		
						Wafer Fab Process		
PCN Details								
Description of Change:								
Texas Instruments is pleased to announce the qualification of new mount compound material for select package device. Devices will remain in current assembly facility and piece part changes as follows:								
Material			From		То			
Mount co	mpound	1400348111		1	1400329111			
Reason for Change:								
Continuity of supply.								
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):								
None								
Anticipated imp	act on Ma	erial De	claration	I				
No Impact to Material Dec		Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the <u>TI Eco-Info website</u> . There is no impact to the material meeting current regulatory compliance requirements with this PCN change.						
Changes to product identification resulting from this PCN:								
None								
Product Affected:								
SN74HC595BRWNR SN74LVC244ARWPR								

Qualification Report

Approve Date 26-Mar-2019

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: <u>SN74LVC244ARWPR</u>
TC	**T/C -65C/150C	-65C/+150C (500 Cycles)	1/77/0
MSL	Moisture Sensitivity (Cu Wire)	(per the appropriate pkg level)	1/12/0
MQ	Manufacturability (Assembly)	(per mfg. Site specification)	Pass
VM	Visual Quality Reliability Inspection	Post Temp Cycle	Pass
YLD	FTY and Bin Summary	-	Pass

- QBS: Qual By Similarity

- Qual Device SN74LVC244ARWPR is qualified at LEVEL1-260C

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

THIS INFORMATION RELATING TO QUALITY AND RELIABILITY IS PROVIDED "AS IS." Product information detailed in this report may not accurately reflect TI's current product materials, processes and testing used in the construction of the TI products. Customers are solely responsible to conduct sufficient engineering and additional qualification testing to determine whether a device is suitable for use in their applications. Using TI products outside limits stated in TI's datasheet may void TI's warranty. See TI's Terms of Sale at "http://www.ti.com/lsds/ti/legal/termsofsale.page"

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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